

OPTIMAL POWER FLOW

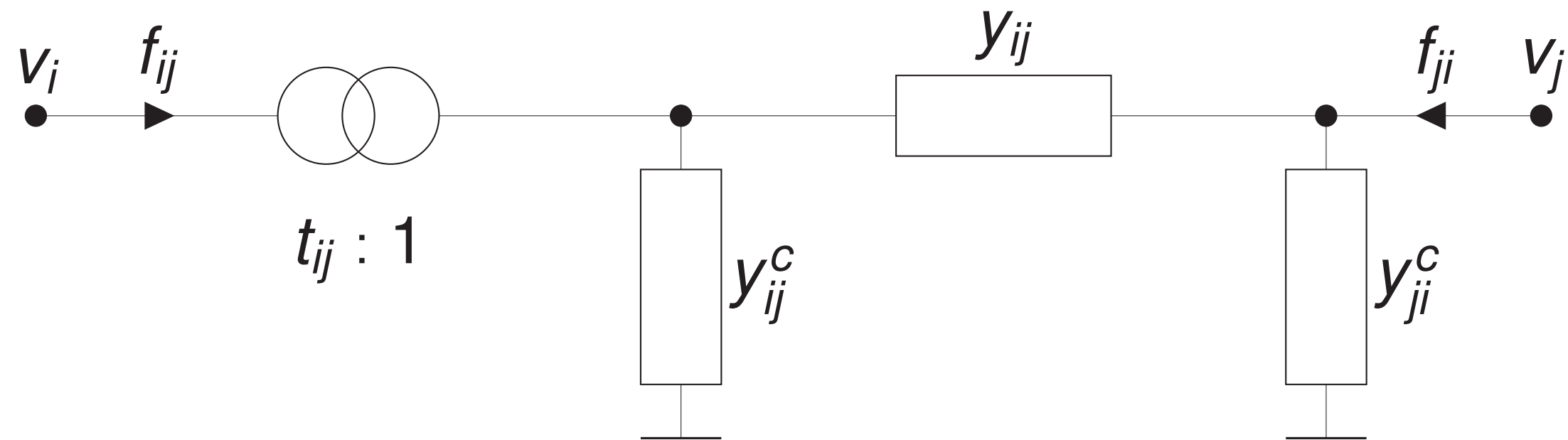


Figure: π -section branch model for edge (i, j) in transmission system.

$$\begin{aligned}
 & \underset{\mathbf{s}^g, \mathbf{v}}{\text{minimize}} && C(\mathbf{s}^g) \\
 & \text{subject to} && \\
 & \text{(generator limits)} && \mathbf{s}_{\min}^g \preceq \mathbf{s}^g \preceq \mathbf{s}_{\max}^g \\
 & \text{(voltage limits)} && \mathbf{v}_{\min} \preceq |\mathbf{v}| \preceq \mathbf{v}_{\max} \\
 & \text{(line flow limits)} && |\mathbf{f}_f| \preceq \mathbf{f}_{\max} \\
 & \text{(line flow limits)} && |\mathbf{f}_t| \preceq \mathbf{f}_{\max} \\
 & \text{(angle difference limits)} && \theta_{\min} \preceq \angle(\mathbf{v}_f \mathbf{v}_t^*) \preceq \theta_{\max} \\
 & \text{(Ohm's law)} && \mathbf{f}_f = (\mathbf{y} + \mathbf{y}_f^c) \frac{|\mathbf{v}_f|^2}{|\mathbf{t}|^2} - \mathbf{y}^* \frac{\mathbf{v}_f \mathbf{v}_t^*}{\mathbf{t}} \\
 & \text{(Ohm's law)} && \mathbf{f}_t = (\mathbf{y} + \mathbf{y}_t^c) \frac{|\mathbf{v}_t|^2}{|\mathbf{t}|^2} - \mathbf{y}^* \frac{\mathbf{v}_f^* \mathbf{v}_t}{\mathbf{t}} \\
 & \text{(energy conservation)} && \mathbf{s}^g - \mathbf{s}^d = (\mathbf{y}^s)^* |\mathbf{v}|^2 + \mathbf{C}_f^T \mathbf{f}_f + \mathbf{C}_t^T \mathbf{f}_t
 \end{aligned}$$

OPF AS A GRAPH SIGNAL PROCESSING PROBLEM

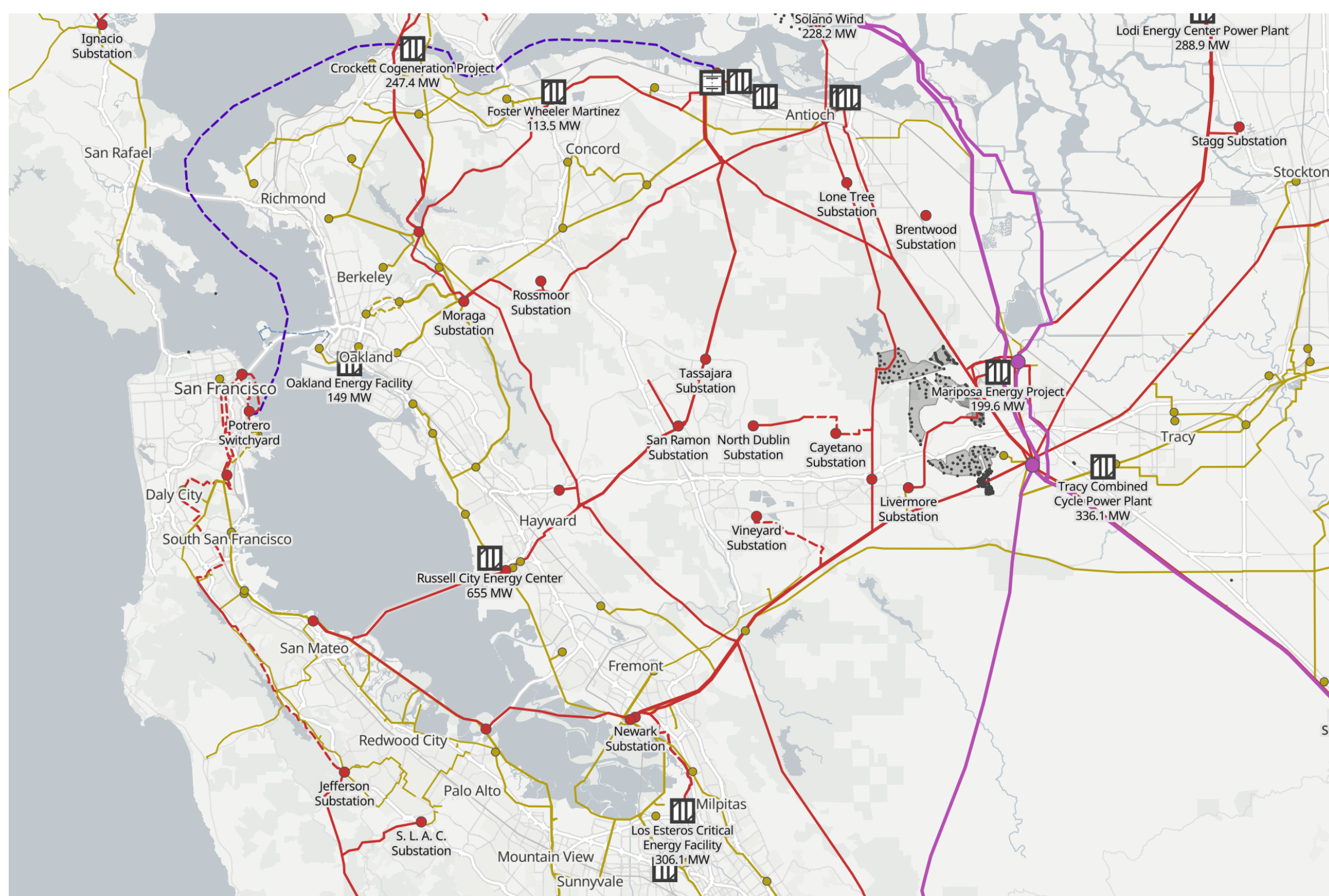


Figure: Map of San Francisco Bay power infrastructure from OpenStreetMap/OpenInfraMap.

- Graph $\mathcal{G} = (\mathcal{V}, \mathcal{E})$:
 - \Rightarrow nodes $i \in \mathcal{V}$ represent buses \Rightarrow generators and loads.
 - \Rightarrow edges $(i, j) \in \mathcal{E}$ represent branches \Rightarrow lines and transformers.
- GNN $\mathbf{X} = \Phi(\mathbf{Z}, \mathcal{H}, \mathcal{G})$ with learnable parameters \mathcal{H} .
 - \Rightarrow Input: $\mathbf{Z} = [\text{Re}(\mathbf{s}^d) \text{Im}(\mathbf{s}^d) \text{Re}(\mathbf{s}_{\min}^g) \text{Im}(\mathbf{s}_{\max}^g) \mathbf{v}_{\min} \mathbf{v}_{\max}] \in \mathbb{R}^{N \times 8}$
 - \Rightarrow Output: $\mathbf{X} = [\text{Re}(\mathbf{s}^g) \text{Im}(\mathbf{s}^g) |\mathbf{v}| \angle \mathbf{v}] \in \mathbb{R}^{N \times 4}$
- Need to find parameters \mathcal{H} that satisfy constraints.

$$\begin{aligned}
 & \underset{\mathcal{H}}{\text{minimize}} && C(\Phi(\mathbf{Z}, \mathcal{H}, \mathcal{G})) \\
 & \text{subject to} && \\
 & \text{(inequality constraints)} && g_i(\mathbf{X}) \preceq 0 && i = 1, \dots, n \\
 & \text{(equality constraints)} && h_i(\mathbf{X}) = 0 && i = 1, \dots, m
 \end{aligned}$$

PENALTY FUNCTION RELAXATION

- Relax inequality $g_i(\mathbf{X})$ by adding penalty ϕ_i .
- Relax equality $h_i(\mathbf{X})$ by adding penalty ψ_i .

$$\begin{aligned}
 \mathcal{H}^* &= \underset{\mathcal{H}}{\text{argmin}} \mathbb{E}_{\mathbf{Z}} [\mathcal{L}(\Phi(\mathbf{Z}, \mathcal{H}, \mathcal{G}))] \\
 \mathcal{L}(\mathbf{X}) &= C(\mathbf{X}) + \sum_{i=1}^n \lambda_i \phi_i(\mathbf{X}) + \sum_{i=1}^m \mu_i \psi_i(\mathbf{X})
 \end{aligned}$$

- The problem is unconstrained with hyperparameters λ_i, μ_i .

NUMERICAL EXPERIMENTS

- Evaluated performance on the IEEE-30 and IEEE-118 systems.
- Generated data by perturbing reference load $\mathbf{s}_{\text{ref}}^d$:

$$\mathbf{s}^d \sim \text{Uniform}(0.9\mathbf{s}_{\text{ref}}^d, 1.1\mathbf{s}_{\text{ref}}^d)$$
- Training on 10,000 unlabeled demand samples.
- Compare GNN against interior point methods (IPOPT).

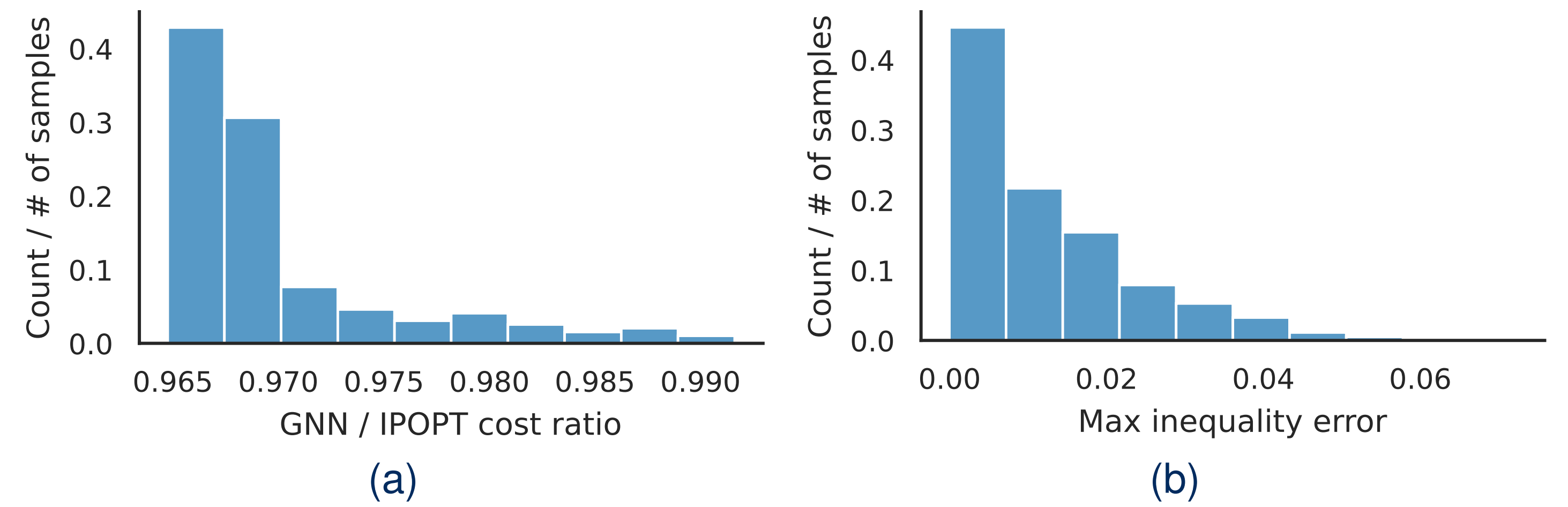


Figure: GNN performance on the IEEE-30 test dataset.

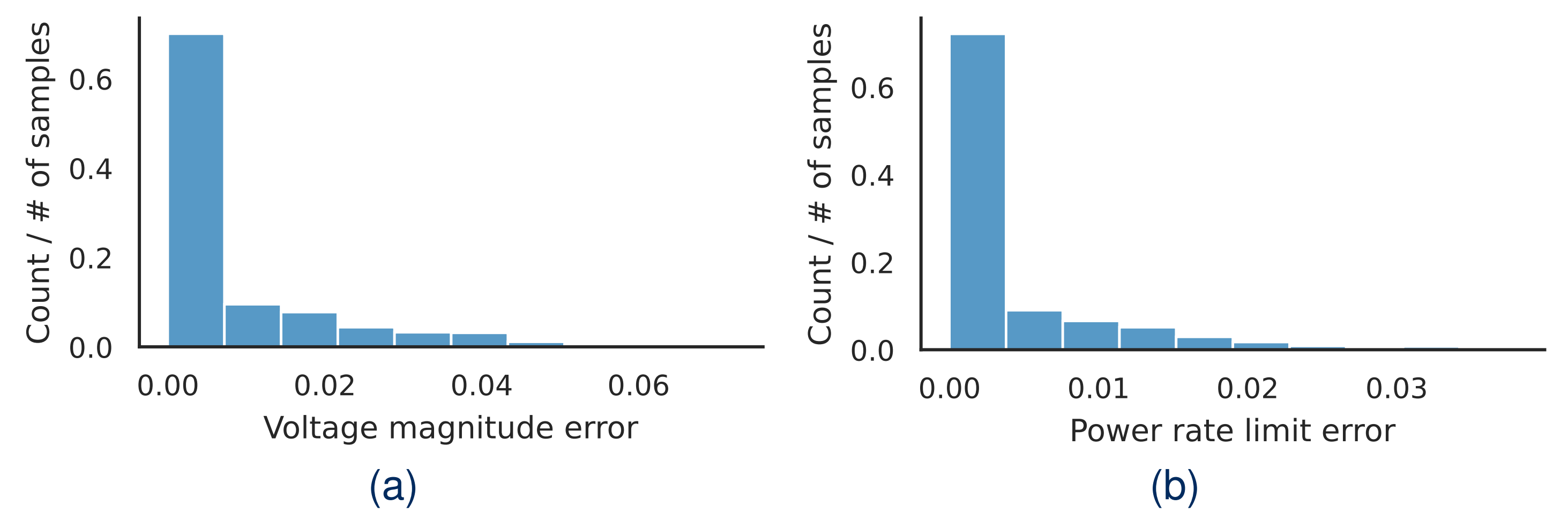


Figure: IEEE-30 constraint violations of (a) voltage magnitude and (b) flow limits.

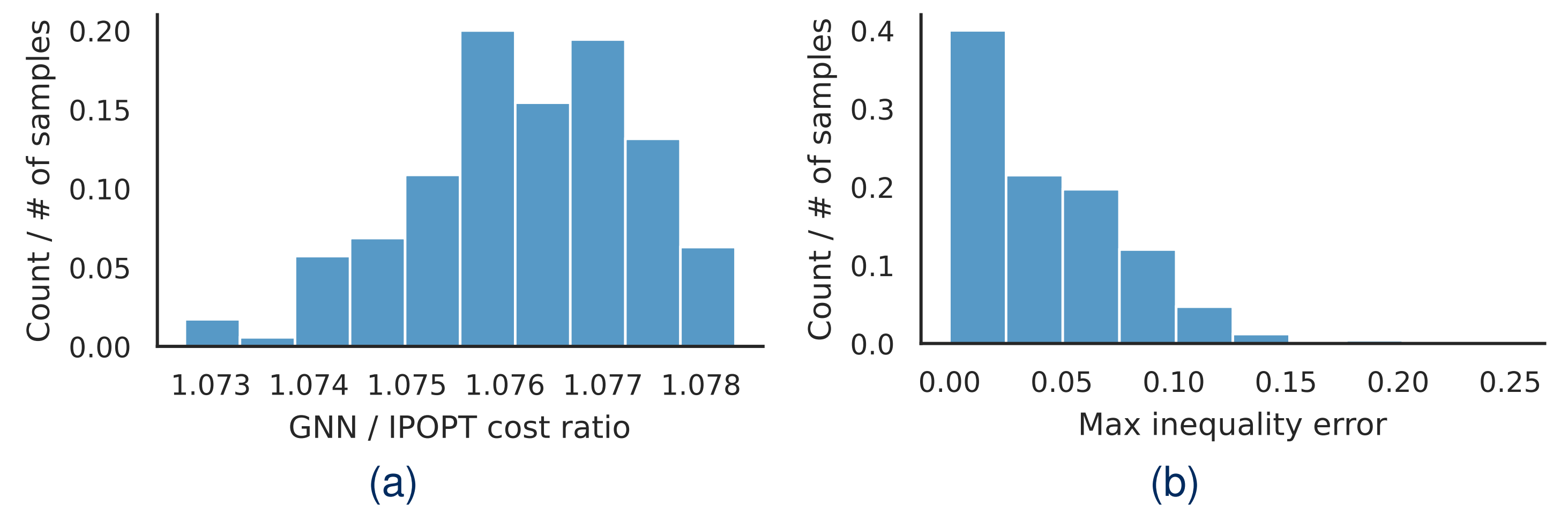


Figure: GNN performance on the IEEE-118 test dataset.

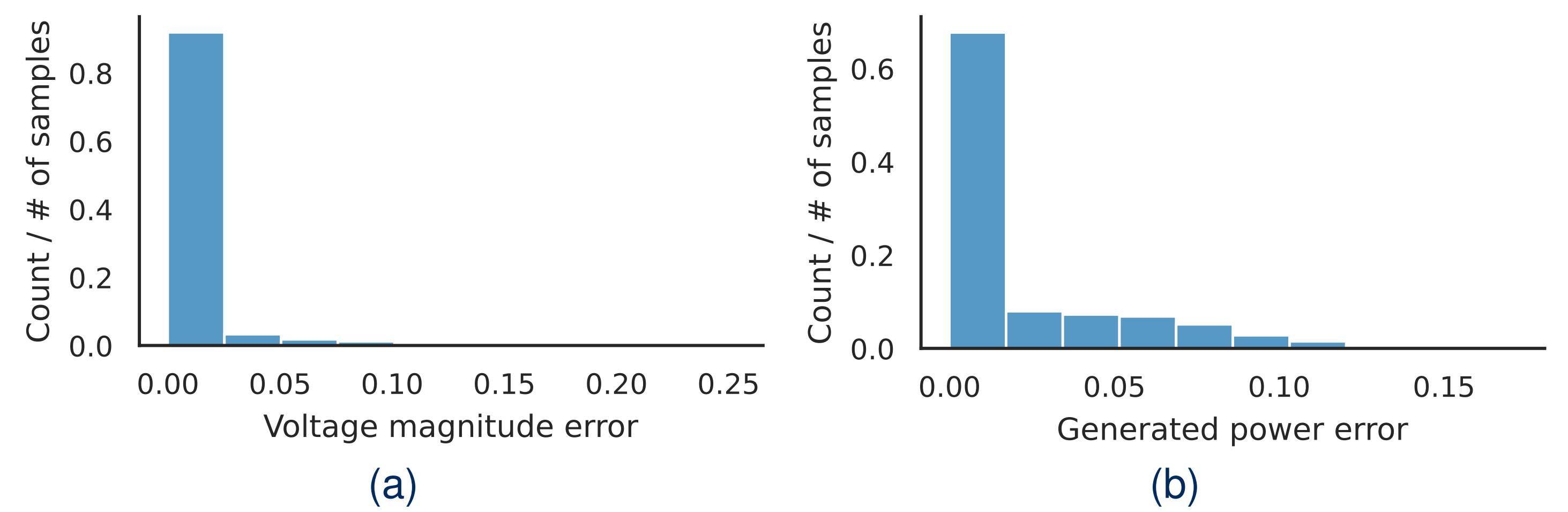


Figure: IEEE-118 constraint violations of (a) voltage magnitude and (b) generation.

RESULTS AND DISCUSSION

- Compared GNN against an interior point method (IPOPT).
 - \Rightarrow On IEEE-30: GNN outperformed IPOPT.
 - \Rightarrow On IEEE-118: higher cost and frequently infeasible.
- Difference between system topologies explains this:
 - \Rightarrow IEEE-30 has binding branch flow limits.
 - \Rightarrow IEEE-118 does not have limits on power flow.

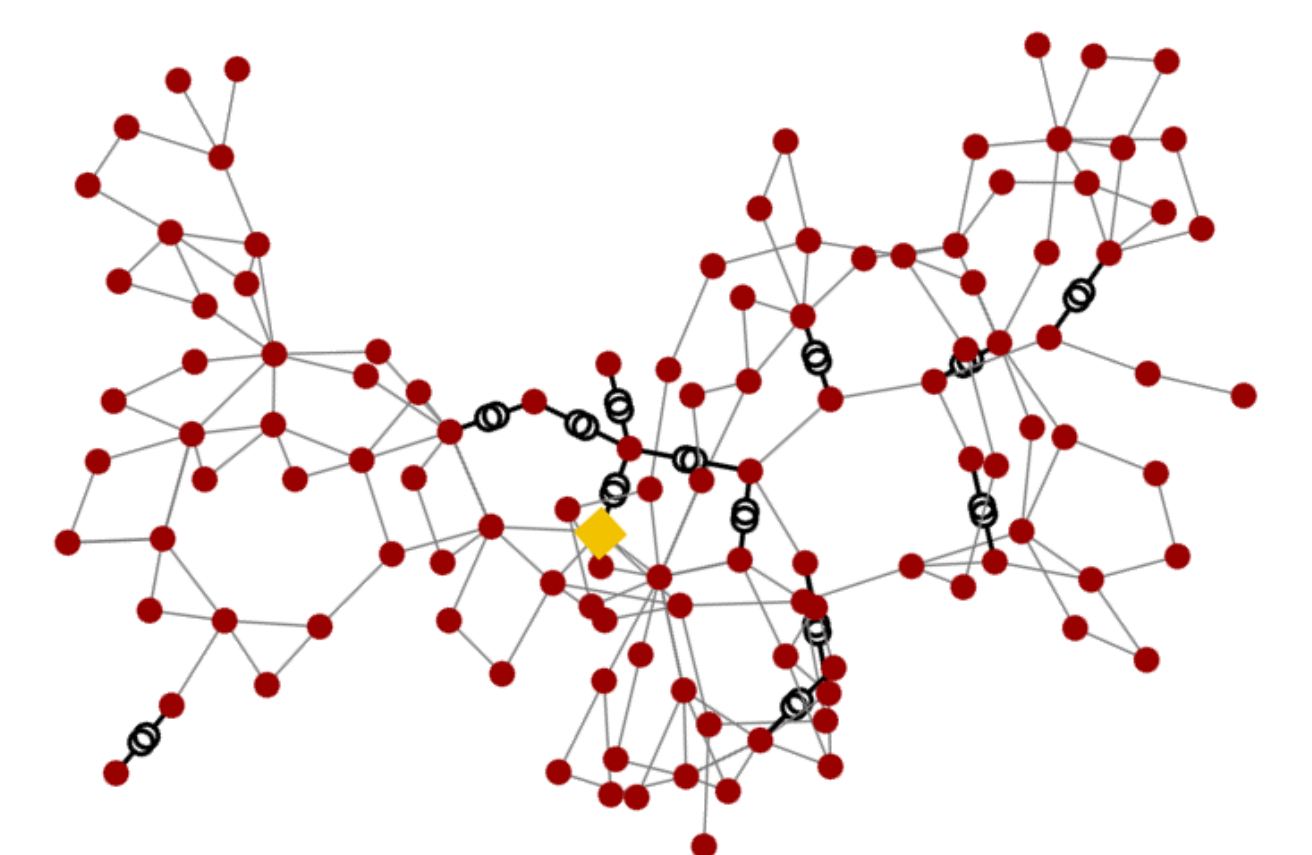


Figure: IEEE-118 Test System Graph